

## Freeform Search

Database:

US Pre-Grant Publication Full-Text Database  
 US Patents Full-Text Database  
 US OCR Full-Text Database  
 EPO Abstracts Database  
 JPO Abstracts Database  
 Derwent World Patents Index  
 IBM Technical Disclosure Bulletins

Term:

L11 not L9

 Display:  Documents in Display Format:  Starting with Number 

 Generate: ☐ Hit List ☒ Hit Count ☐ Side by Side ☐ Image

Search

Clear

Interrupt

### Search History

 DATE: Monday, December 20, 2004    [Printable Copy](#)    [Create Case](#)
**Set Name Query**

side by side

**Hit Count Set Name**

result set

*DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR*

|            |  |       |            |
|------------|--|-------|------------|
| <u>L12</u> | L11 not L9   | 93    | <u>L12</u> |
| <u>L11</u> | L8 and ((monitor\$3 or inspect\$4 or measur\$5 or map\$4) with (dos\$3 or implant\$5)) | 108   | <u>L11</u> |
| <u>L10</u> | L8 and ((monitor\$3 or inspect\$4 or measur\$5 or map\$4) with (dos\$3 or implant\$5)) | 108   | <u>L10</u> |
| <u>L9</u>  | L8 and (wafer with map\$4)   | 27    | <u>L9</u>  |
| <u>L8</u>  | L6 and (surface with reflectivity)   | 469   | <u>L8</u>  |
| <u>L7</u>  | L6 and (surface with reflectivity)   | 0     | <u>L7</u>  |
| <u>L6</u>  | (wafer or semiconductor) same (ion with implant\$6)                                    | 54532 | <u>L6</u>  |
| <u>L5</u>  | 5333049.pn.  | 2     | <u>L5</u>  |
| <u>L4</u>  | L3 and (incoherent or non-destructive)   | 23    | <u>L4</u>  |
| <u>L3</u>  | wafer and (relative adj reflectivity)  | 90    | <u>L3</u>  |
| <u>L2</u>  | (relative with reflectivity with wafer)  | 37    | <u>L2</u>  |
| <u>L1</u>  | (map with relative with reflectivity with wafer)                                       | 0     | <u>L1</u>  |

END OF SEARCH HISTORY